Search Notes			

Application/Control No.	Applicant(s)/Patent under Reexamination
10/706,987	TEI ET AL.
Examiner	Art Unit
Helen L. Pezzuto	1713

SEARCHED				
Class	Subclass	Date	Examiner	
526	333			
	336	3/17/2006	HP	
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
i				

SEARCH (INCLUDING SEAR	NOTES CH STRATEGY	)
	DATE	EXMR
STIC STN search	2/15/2006	HP
West, Inventors search	3/17/2006	HP